

# Atomistic Simulation of Carbon Nanotube FETs Using Non-Equilibrium Green's Function Formalism

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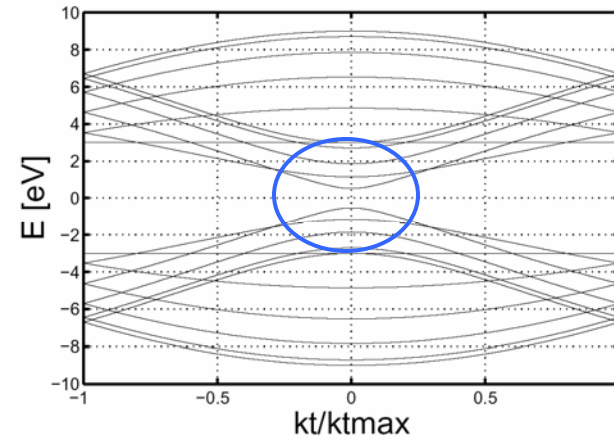
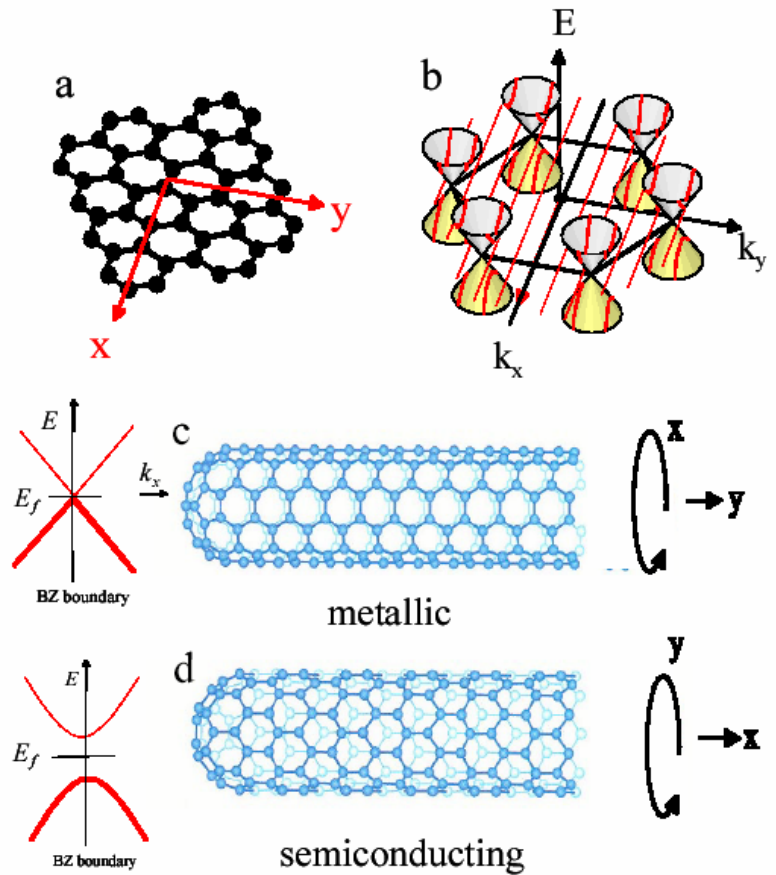
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1. Introduction
2. NEGF Formalism
3. Ballistic CNTFETs
4. Summary

# Introduction: carbon nanotubes



$$E(k) = \pm \left( \frac{E_G}{2} \right) \sqrt{1 + (3kd/2)^2}$$

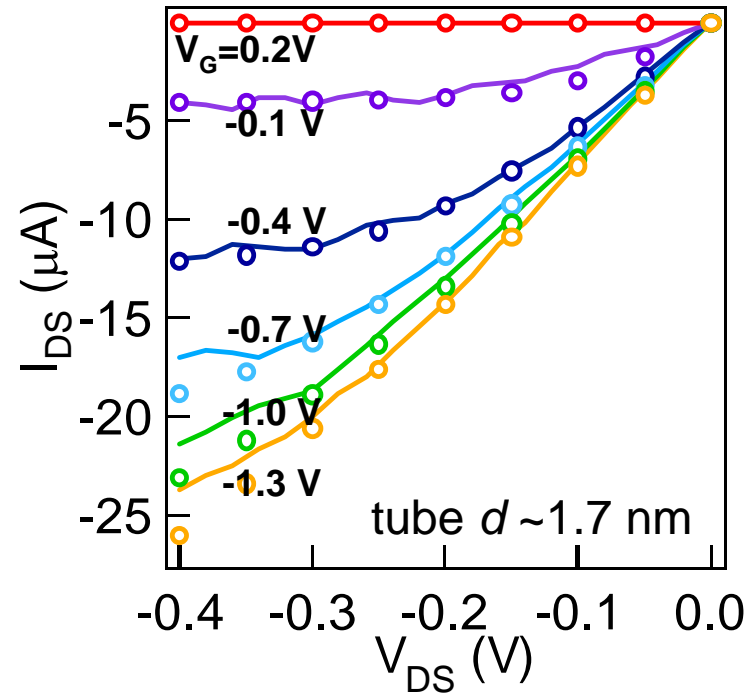
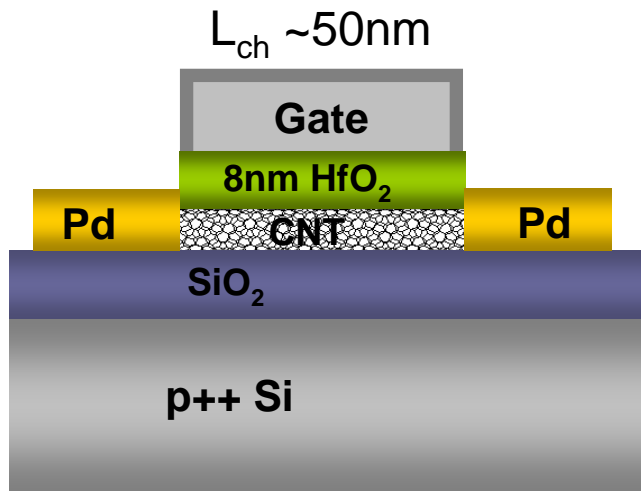
$$E_G \approx 0.8eV/d(\text{nm})$$

McEuen et al., *IEEE Trans. Nanotech.*, **1**, 78, 2002.

(see also: R. Saito, G. Dresselhaus, and M.S. Dresselhaus, *Physical Properties of Carbon Nanotubes*, Imperial College Press, London, 1998.)

# Introduction: device performance

nanotube diameter  $\sim 1.7$  nm



$$I_{ON} \approx 3,000 \mu\text{A} / \mu\text{m} \quad (W = 2d)$$

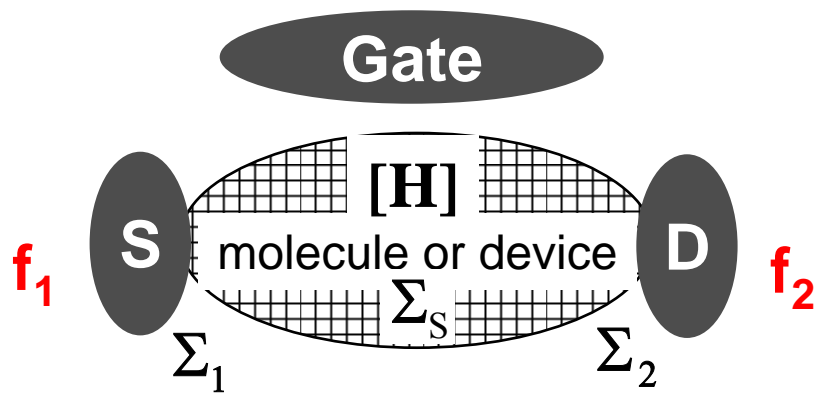
Javey, Guo, Farmer, Wang, Yenilmez, Gordon, Lundstrom, and Dai, Nano Lett., 2004

# Outline

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# Nonequilibrium Green's Function (NEGF)



$$\mathbf{G} = [\mathbf{E}\mathbf{I} - \mathbf{H} - \underbrace{\Sigma_1 - \Sigma_2}_{\text{contacts}} - \Sigma_S]^{-1}$$

device
contacts
scattering

## Charge density (ballistic)

$$N = \int [D_1(E)f_1(E) + D_2(E)f_2(E)]dE$$

## Current

$$I_D = \frac{2q}{h} \int T(E)(f_1(E) - f_2(E))dE$$

$$D_{1,2}(E) = \frac{1}{2\pi} \mathbf{G}\Gamma_{1,2}\mathbf{G}^+$$

$$T(E) = \text{Trace}[\Gamma_1\mathbf{G}\Gamma_2\mathbf{G}^+]$$

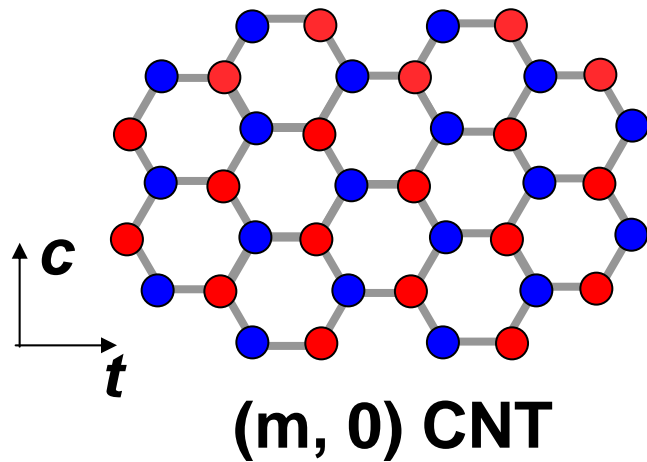
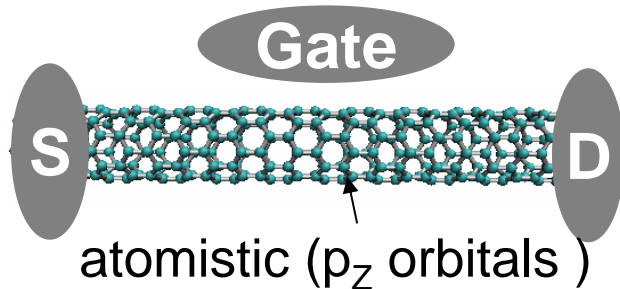
$$\Gamma_{1,2} = i[\Sigma_{1,2} - \Sigma_{1,2}^+]$$

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# CNTFETs: real-space basis (ballistic)



$$H = \begin{array}{c} \Sigma_S \swarrow \\ \begin{array}{|c|c|c|c|} \hline U_1 & t & & \\ \hline U_1 & t & & \\ \hline U_1 & t & & \\ \hline U_1 & t & & \\ \hline t & U_2 & t & \\ \hline t & t & U_2 & \\ \hline t & t & U_2 & \\ \hline t & t & U_2 & \\ \hline t & t & t & \\ \hline & t & U_3 & t \\ \hline & t & U_3 & t \\ \hline & t & U_3 & t \\ \hline & t & U_3 & t \\ \hline & t & t & U_4 \\ \hline & t & t & U_4 \\ \hline & t & t & U_4 \\ \hline & t & t & U_4 \\ \hline & & & \\ \hline \end{array} \\ \searrow \Sigma_D \end{array}$$

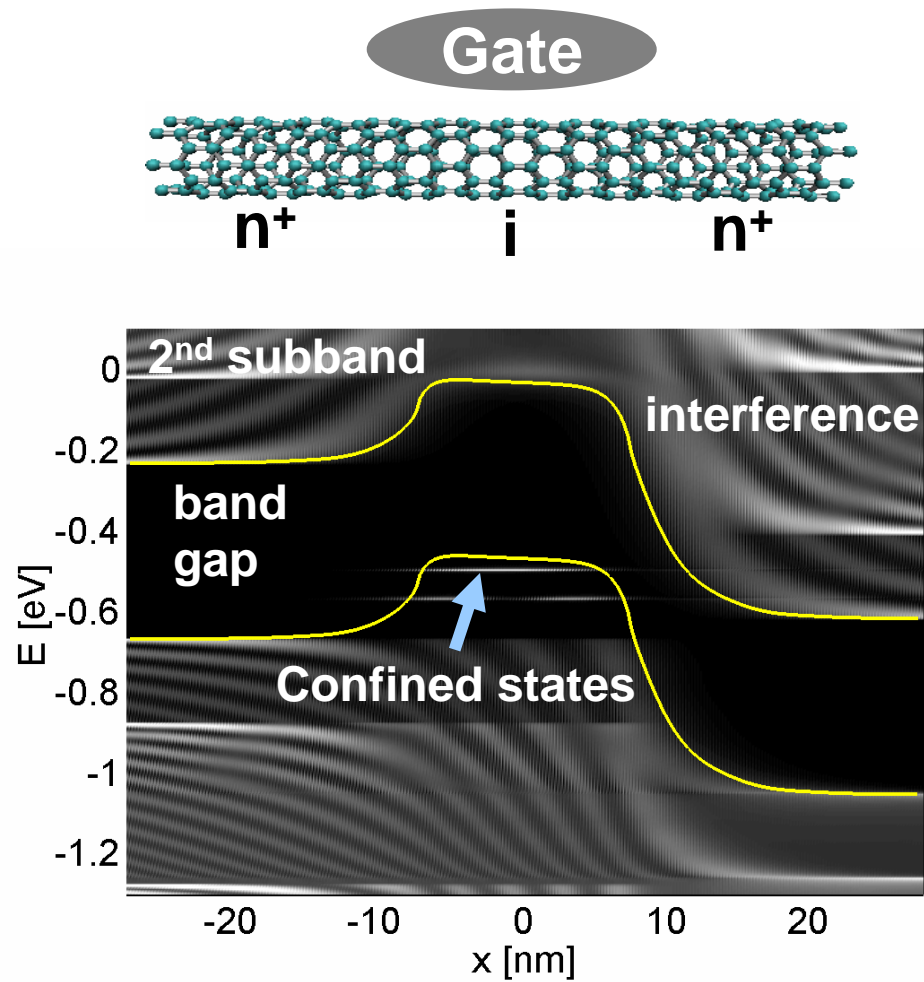
$$\Sigma_S = \begin{bmatrix} [\tau g_S \tau^+] & 0 & 0 \\ 0 & 0 & 0 \\ 0 & 0 & 0 \\ & & & O \end{bmatrix} \quad \Sigma_D = \begin{bmatrix} O & & & \\ & 0 & 0 & 0 \\ & 0 & 0 & 0 \\ & 0 & 0 & [\tau g_D \tau^+] \end{bmatrix}$$

$$G^r = [EI - H - \Sigma_S - \Sigma_D]^{-1}$$

Recursive algorithm for  $G^r$ :  $O(m^3N)$

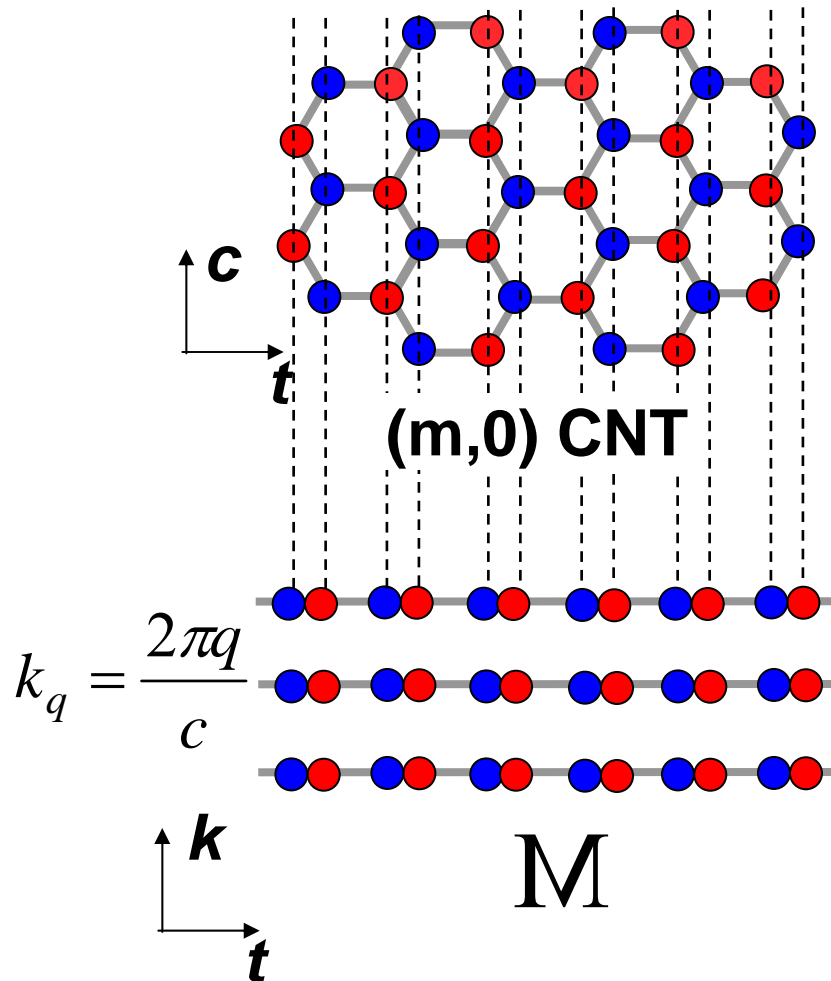
Lake et al., JAP, **81**, 7845, 1997

# CNTFETs: real-space results





# CNTFETs: mode-space approach (ballistic)

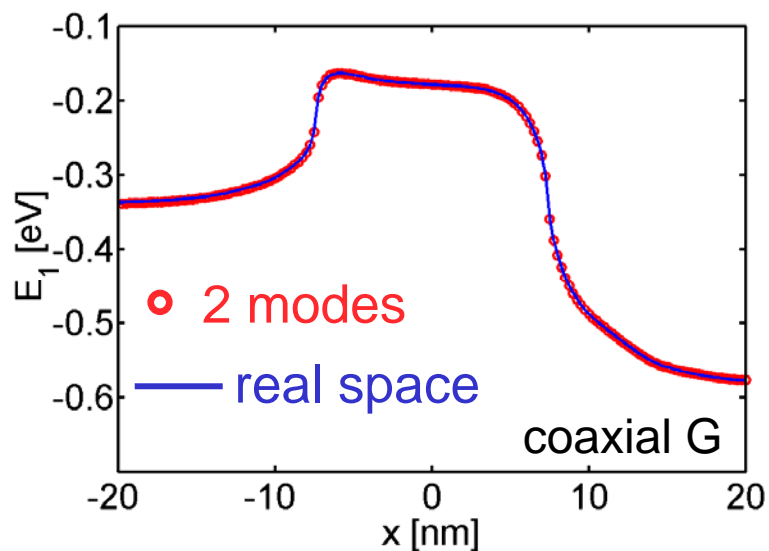
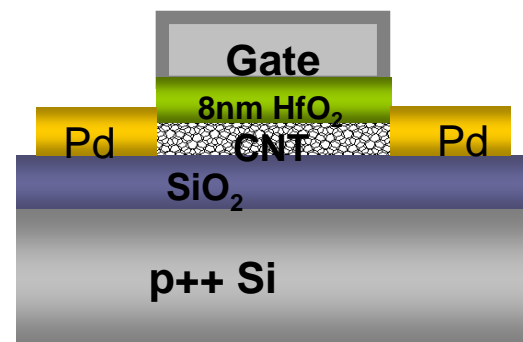
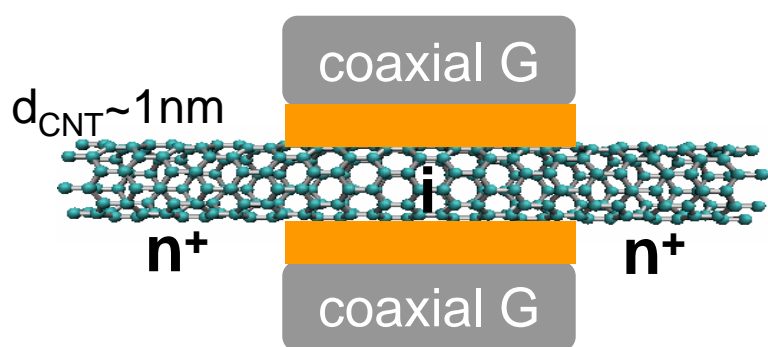


## The $q$ th mode

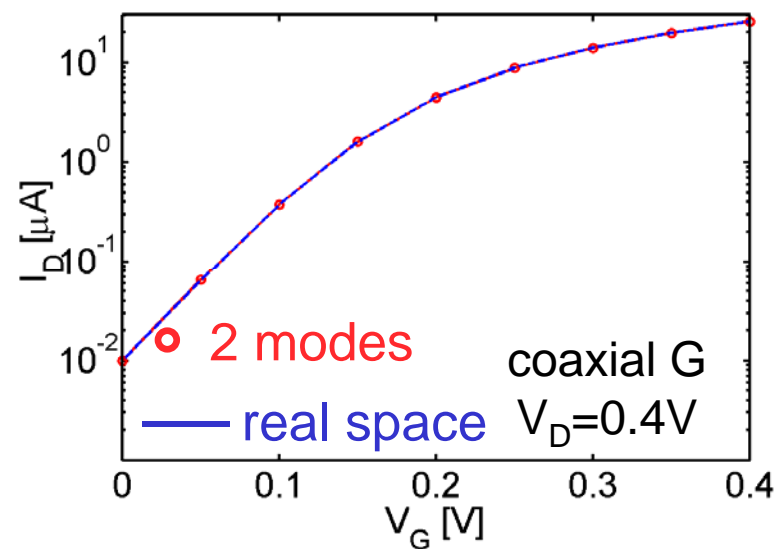
$$H_q = \begin{bmatrix} u_1 & b_q & & & \\ b_q & u_2 & t & & \\ & t & u_3 & O & \\ & & O & O & b_q \\ & & & b_q & u_N \end{bmatrix}$$

- $\Sigma_S (1,1)$  and  $\Sigma_D (N,N)$  analytically computed
- **Computational cost:  $O(N)$**   
real space  $O(m^3N)$

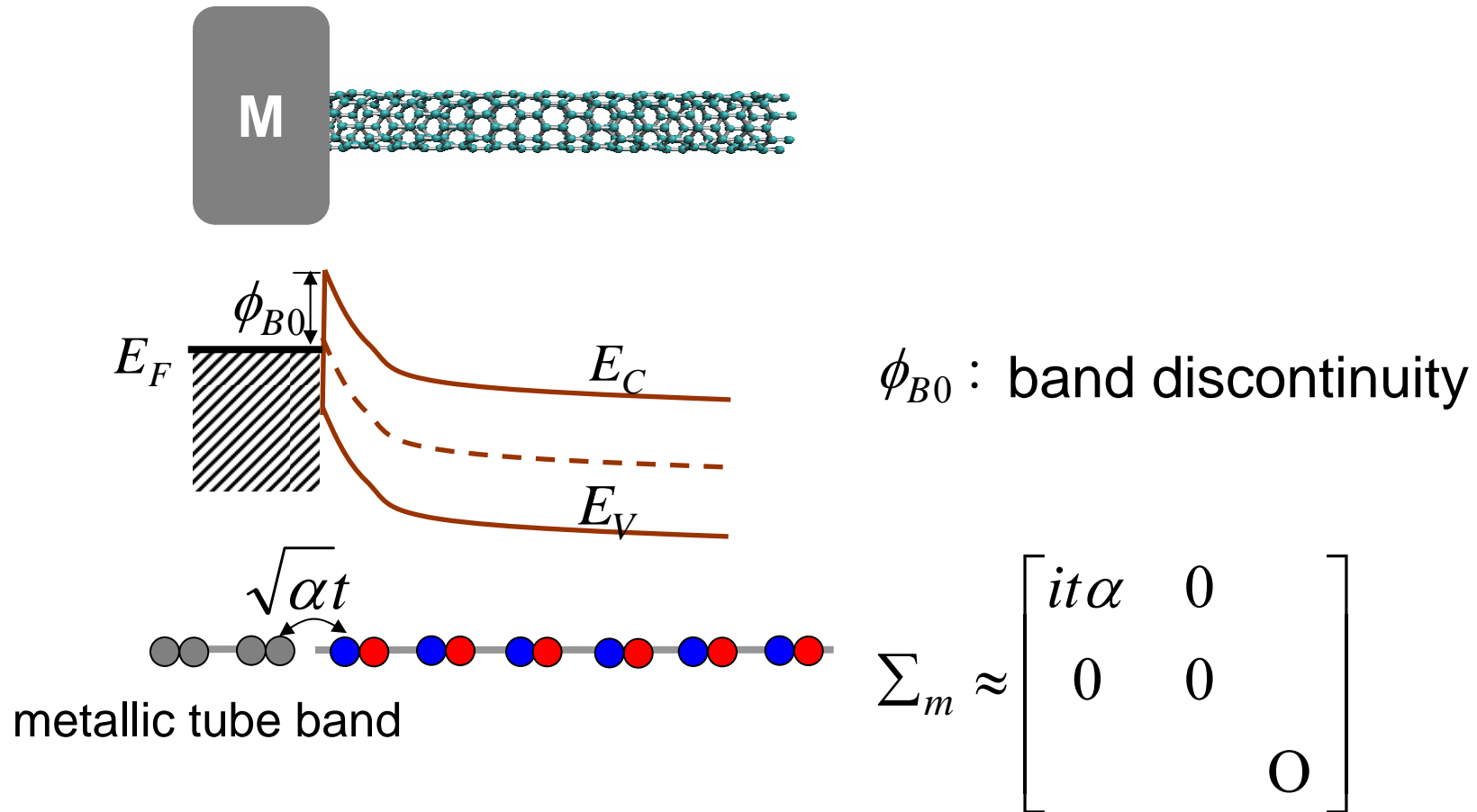
# CNTFETs: mode-space results



band profile (ON)

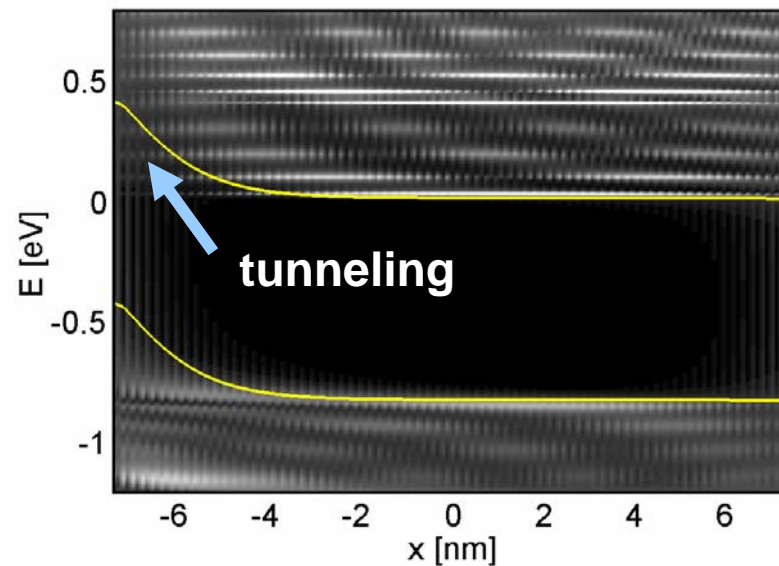
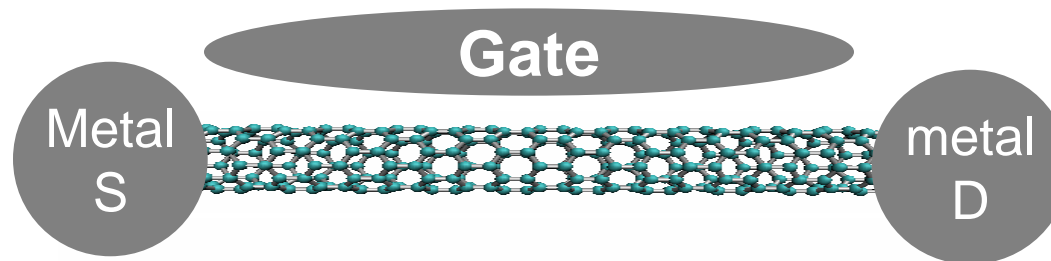


# CNTFETs: treatment of M/CNT contacts



Kienle et al, *ab initio* study of contacts in progress

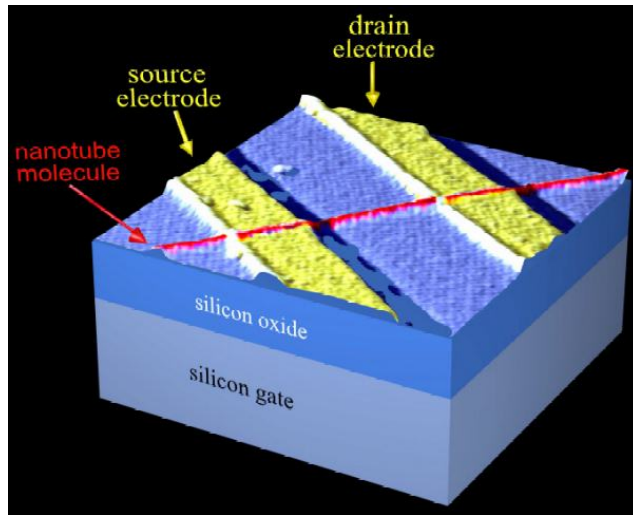
# CNTFETs: treatment of M/CNT contacts



$$V_D = V_G = 0.4V$$

Charge transfer in unit cell: Leonard et al., APL, **81**, 4835, 2002

# CNTFETs: 3D Poisson solver



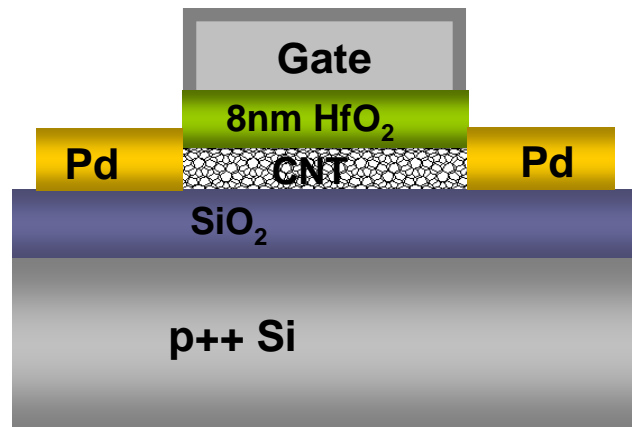
**Method of moments:**

$$V(\vec{r}) = \int K(\vec{r} - \vec{r}') \rho(\vec{r}') d\vec{r}'$$

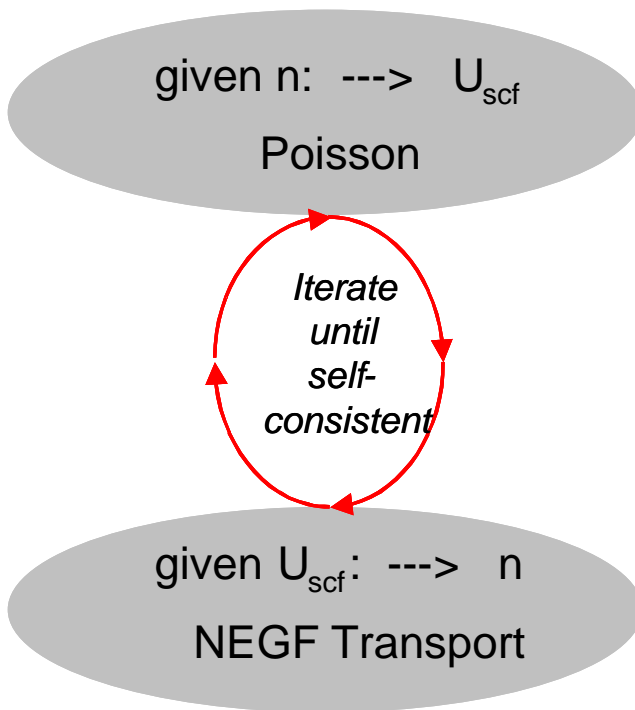
**Electrostatic kernel:**

$$K(\vec{r} - \vec{r}')$$

$K(\vec{r} - \vec{r}')$  for 2 types of dielectrics available in Jackson, *Classical Electrodynamics*, 1962

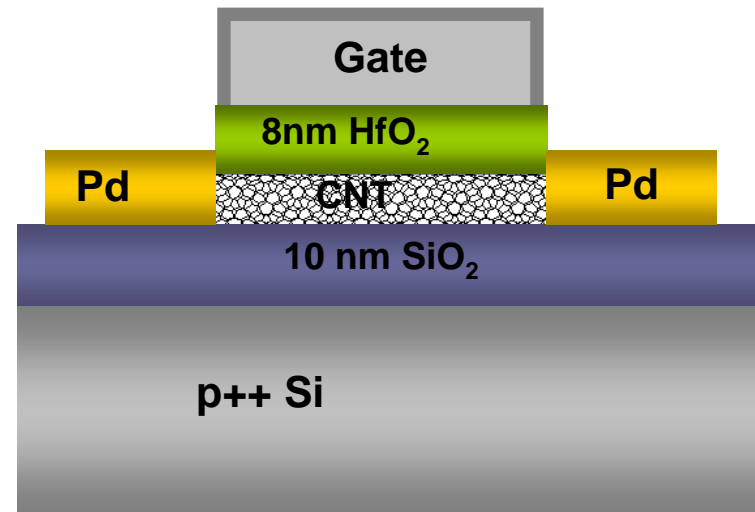
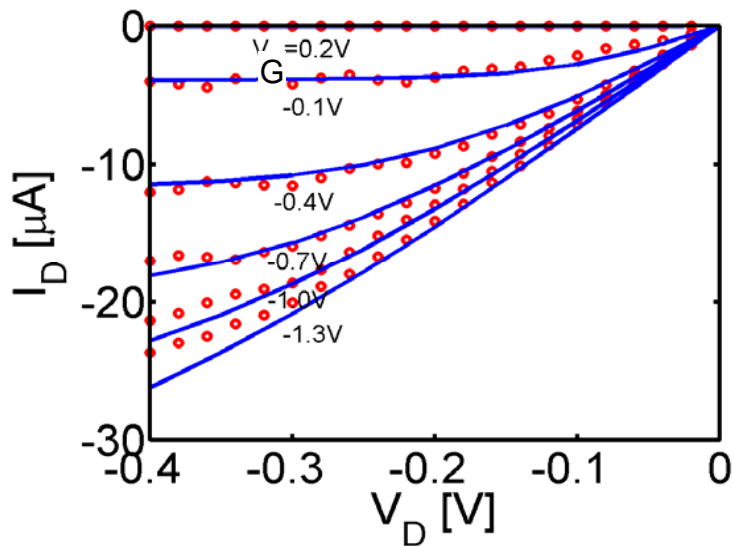
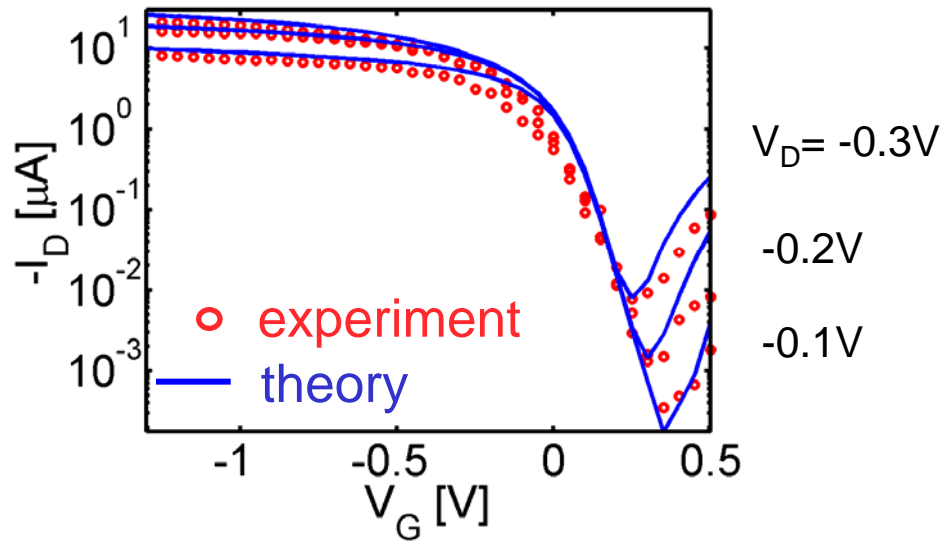


# CNTFETs: numerical techniques



- **Non-linear Poisson**
- **Recursive algorithm for**  
$$G(E) = [EI - H - \Sigma_S - \Sigma_D]^{-1}$$
- **Gaussian quadrature for doing integral**
- **Parallel different bias points**
- **~20min for full I-V of a 50-nm CNTFET**

# CNTFETs: theory vs. experiment



Javey, et al., *Nano Letters*, **4**, 1319, 2004

$$\phi_{Bp}=0$$

$$d_{CNT} \sim 1.7\text{nm}$$

$$R_S=R_D \sim 1.7\text{K}\Omega$$

# Summary

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A simulator for ballistic CNTFETs is developed

- atomistic treatment of the CNT
- 3D electrostatics
- phenomenological treatment of M/CNT contacts
- efficient numerical techniques

Theory is calibrated to experiment